

FORM PTO-1449 (Colb)	ATTY DOCKET NO. IL9-2000-0079	SERIAL NUMBER 09/847,309
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS' INFORMATION STATEMENT	APPLICANT Alan HARTMN, et al.	
JUL 30 2001 U.S. PATENT & TRADEMARK OFFICE	FILING DATE May 3, 2001	GROUP ART UNIT 2184

U.S. PATENT DOCUMENTS

Examiner's Initials		DOCUMENT NO.	DATE	NAME	CLASS	SUB	FILING DATE
TC	AA	5,394,347	Feb. 1995	Kita et al.			
	AB	5,623,499	Apr. 1997	Ko et al.			RECEIVED
	AC	5,918,037	June 1999	Tremblay et al.			JUL 31 2001
TC	AD	4,991,176	Feb. 1991	Dahbura et al.			Technology Center 2100
	AE						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB	TRANSLATION
	AF						

OTHER ART (Including Author, Bills, Pertinent Pages, Etc.)

TC	AG	I. Gronau et al., "A Methodology and Architecture for Automated Software Testing", IBM Research Laboratory in Haifa Technical Report, 17 pages, Oct. 2000, Haifa, Israel.
	AH	"Murphi Description Language and Verifier", previously overviewed in "Protocol Verification as a Hardware Design Aid", by D.L. Dill et al., 1992 IEEE International Conference on Computer Design: VSLI in Computers and Processors, IEEE Computer Society, pp. 522-525, and last updated May 1996, 5 pages. (http://sprout.stanford.edu/dill/murphi/html)
	AI	Ilan Gronau, et al., "Methodology and architecture for automated software testing", January 11, 2000. (http://www.geocities.com/model_based_testing//online_papers.htm).
TC	AJ	Brian Marick, "The craft of software testing", 1995, Chap. 5, p. 132.

EXAMINER:

DATE CONSIDERED:

5/9/04

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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<i>TF</i>	AG	Boris Beizer, "Software testing techniques", Second Edition, 1990, pp. 23-24.
<i>TF</i>	AH	R. Burke, "Black-box regression testing – an automated approach", Fifth International Conference on Testing Computer Software, Washington, DC, June 1988 (pp. 455,481 in Boris Beizer's Book "Software testing techniques", Second Edition, 1990)
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